Corelis Extends JTAG Embedded Testing to Freescale i.MX51

Corelis announced ScanExpress JET support for all members of the Freescale i.MX51 family of applications processors. ScanExpress JTAG Embedded Test (JET) provides at-speed testing of embedded processor-based electronic printed circuit boards and systems
to detect, isolate, and diagnose structural and functional defects with minimal development and
investment.

ScanExpress JET controls the i.MX51's ARM Corte -A8 core through the JTAG debug port, enabling development and execution of binary and script test steps using a graphical user interface on the host PC. Benefits of using ScanExpress JET for i.MX51 applications processors include:

• Standardized interface tests for SDRAM memory, I2C, Ethernet, PMIC, and UART
• Fast in-system programming and testing of parallel and serial NOR and NAND Flash
• Fully automatic test development for all supported peripherals
• Integrated scripting environment for test customization
• No boot code requirement for test execution

Freescale i.MX51 applications processors offer low power, efficient multimedia processing and are targeted at consumer, industrial, automotive, and general embedded applications, representing an ideal platform for ScanExpress JET. "Systems built around the i.MX51 are often designed to fit a particular form factor and need to be highly reliable," explains Ryan Jones, Senior Technical

Marketing Engineer at Corelis. "These constraints contribute to the need for automated nonintrusive, at-speed functional tests. ScanExpress JET offers significant functional test coverage with minimal impact on the system design—a simple JTAG connection offers complete control over the CPU allowing convenient and reusable tests for development and production."

To receive additional education on the benefits of embedded testing, download the ScanExpress JET whitepaper today at
http://www.corelis.com/whitepapers/ScanExpressJET_Whitepaper.htm [1].

Posted by Janine E. Mooney, Editor

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